

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Cancelled).

2. (Previously Presented) A corrosion-resistive member having a corrosion-resistive face which is exposed to a corrosive gas causing ion bombardment, wherein at least a part of said corrosion-resistive member comprises a sintered silicon nitride body having an open porosity of not more than 5%, wherein the total content of elements in Group Ia and Groups 4a - 3b of the Periodic Table present in said sintered silicon nitride body is not more than 50 ppm by weight, and wherein said sintered silicon nitride body constitutes said corrosion-resistive face;

wherein if two auxiliary planes are formed by cutting said corrosion-resistive member to intersect vertically with said corrosion-resistive face and to be located vertically with respect to each other, an orientation index between said two auxiliary planes is in a range of 0.8 to 1.2, and an orientation index between said corrosion-resistive face and each of said auxiliary faces is not less than 1.5;

wherein said orientation index between the two auxiliary planes satisfies the following formula:

$$[Is1(320)/(Is1(320) + Is1(002))]/[Is2(320)/(Is2(320) + Is2(002))];$$

wherein Is1(320) denotes an intensity of X-ray diffraction at a 320 face of β -type silicon nitride in one "Is1" of the auxiliary planes; Is1(002) denotes an intensity of X-ray diffraction at a 002 face of β -type silicon nitride in the auxiliary planes "Is1"; Is2(320) denotes an intensity of X-ray diffraction at a 320 face of β -type silicon nitride in the other auxiliary plane "Is2"; and Is2(002) denotes an intensity of X-ray diffraction at a 002 face of β -type silicon nitride in the auxiliary planes "Is2"; and

wherein said orientation index between said corrosion-resistive face and each of said auxiliary planes satisfies the following formula:

$$[\text{Im}(320)/(\text{Im}(320) + \text{Im}(002))]/[\text{Is}(320)/(\text{Is}(320) + \text{Is}(002))];$$

wherein $\text{Im}(320)$ denotes an intensity of X-ray diffraction at a 320 face of β -type silicon nitride in the corrosion-resistive face "m"; $\text{Im}(002)$ denotes an intensity of X-ray diffraction at a 002 face of β -type silicon nitride in the corrosion-resistive face "m"; $\text{Is}(320)$ denotes an intensity of X-ray diffraction at a 320 face of β -type silicon nitride in the auxiliary plane "Is"; and $\text{Is}(002)$ denotes an intensity of X-ray diffraction at a 002 face of β -type silicon nitride in the auxiliary planes "Is".

3-9. (Cancelled)

10. (Previously Presented) The corrosion-resistive member set forth in claim 2, wherein one or more metal elements selected from Group 2a and Group 3a in the Periodic Table are present in a total amount of 1 to 15 mol% in said sintered silicon nitride body as calculated externally in the form of the metal elements relative to said silicon nitride.

11. (Previously Presented) The corrosion-resistive member set forth in claim 10, wherein said sintered silicon nitride body further comprises one or more elements selected from the group consisting of calcium, strontium, barium, magnesium, yttrium and lanthanoid elements.

12. (Previously Presented) The corrosion-resistive member set forth in claim 11, wherein said sintered silicon nitride body comprises one or more elements selected from the group consisting of magnesium, yttrium, cerium, samarium and lanthanum.

13. (Previously Presented) The corrosion-resistive member set forth in claim 10, wherein at least one of said one or more metal elements selected from Group 2a and Group 3a in the Periodic Table is in the form of an oxide.
14. (Previously Presented) The corrosion-resistive member set forth in claim 2, wherein said corrosion-resistive member has a thermal conductivity of 50 W/m·K or less.
15. (Previously Presented) The corrosion-resistive member set forth in claim 2, wherein said corrosive gas is a halogen-based corrosive gas or a plasma of said halogen-based corrosive gas.
16. (Previously Presented) A semiconductor-producing article comprising a substrate comprising said corrosion-resistive members set forth in claim 2.